## Notice of References Cited Application/Control No. 10/829,666 Examiner Peter J. Macchiarolo Applicant(s)/Patent Under Reexamination EDEN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0080688	05-2003	Eden et al.	315/169.3
*	В	US-2006/0038490	02-2006	Eden et al.	313/582
*	С	US-2006/0071598	04-2006	Eden et al.	313/631
*	D	US-2007/0108910	05-2007	Eden et al.	313/631
*	Ε	US-6,016,027	01-2000	DeTemple et al.	313/356
*	F	US-6,194,833	02-2001	DeTemple et al.	313/631
*	G	US-6,867,548	03-2005	Eden et al.	. 315/56
*	Н	US-7,026,640	04-2006	Nathan et al.	257/9
	-	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-		·	

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р			7 - 1		
	ø					
	R					
	S					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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